

**Search Notes**

Application/Control No.

10/511,792

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

RADENNE ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E21.501, E23.064 & E23.14	9/17/2006	C.C.
257	681	9/17/2006	C.C.
235	492	9/17/2006	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/17/2006	C.C.